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Contract

Plasma Focused Ion Beam and Gallium Focused Ion Beam Microscopes

University of Bristol

F03: Contract award notice

Notice identifier: 2022/S 000-036382
Procurement identifier (OCID): ocds-h6vhtk-036add
Published 22 December 2022, 1:03pm

Section I: Contracting authority

I.1) Name and addresses

University of Bristol

4th Floor, Augustine's Courtyard, Orchard Lane

Bristol

BS1 5DS

Email

yi19222@bristol.ac.uk

Telephone

+44 01179289000

Country

United Kingdom

Region code

UK - United Kingdom

Internet address(es)

Main address

www.bristol.ac.uk

I.4) Type of the contracting authority

Body governed by public law

I.5) Main activity

Education

Section II: Object

II.1) Scope of the procurement

II.1.1) Title

Plasma Focused Ion Beam and Gallium Focused Ion Beam Microscopes

II.1.2) Main CPV code

- 38512100 - Ion microscopes

II.1.3) Type of contract

Supplies

II.1.4) Short description

This notice has been issued as a revision of notice 2022/S 000-035764 published on 16th December 2022. This notice contained incorrect weightings on the technical and cost criteria.

The IAC at UoB has identified a need to procure a Plasma-Focused Ion Beam (PFIB) system, which allows for:

• Dual-beam capability with field emission gun scanning electron microscopy (FEGSEM) and plasma-based focused ion beam,

- Micromachining with high milling rates,

- Sample liftout (size reduction),

- Tomography with analytical capability – integrating energy-dispersive X-ray (EDX) and electron backscatter diffraction (EBSD) bought separately from a third party supplier,

- Gas injection using XeF2 enhanced etch, insulator, platinum and carbon, with options of other gas species.

- Cryogenic stage and vacuum transfer capability,

- Preparation of specimens for transmission electron microscopy (TEM) while minimising FIB-induced damage, atom probe tomography (APT) and micromechanical testing.

- Electrical feedthroughs for in-situ characterisation (minimum four channels for four-point resistance measurements).

In addition to the procurement of the PFIB instrument, UoB would like to also as part of this call upgrade the gallium focused ion beam (Ga-FIB) capability of the IAC facility, by procurement of a new Ga-FIB instrument, with the capability for:

- Dual-beam capability with FEGSEM and gallium focused ion beam

- Micromachining and imaging,

- Microcantilever manipulation of specimens for TEM, APT and micromechanical liftouts,

- Gas injection using XeF2 enhanced etch, insulator and organo-metallics containing platinum, with options of other gas species.

Both of these instruments will be utilized within the Interface Analysis Centre (IAC) microscopy and materials facility at UoB, which will be used by a large number of researchers from a large number of UK, European and worldwide Universities, Research Institutes and Industry, thus the equipment and associated software must be simple and straightforward to use, robust and also be sufficiently interlocked to protect the system against accidental misuse.

II.1.6) Information about lots

This contract is divided into lots: No

II.1.7) Total value of the procurement (excluding VAT)

Value excluding VAT: £1,790,000

II.2) Description

II.2.3) Place of performance

NUTS codes

- UK - United Kingdom

II.2.4) Description of the procurement

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II.2.5) Award criteria

Quality criterion - Name: Technical / Weighting: 80

Cost criterion - Name: Price / Weighting: 20

II.2.11) Information about options

Options: No

II.2.13) Information about European Union Funds

The procurement is related to a project and/or programme financed by European Union funds: No

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Section IV. Procedure

IV.1) Description

IV.1.1) Type of procedure

Open procedure

IV.1.8) Information about the Government Procurement Agreement (GPA)

The procurement is covered by the Government Procurement Agreement: Yes

IV.2) Administrative information

IV.2.1) Previous publication concerning this procedure

Notice number: 2022/S 000-026656

Section V. Award of contract

Contract No

Lab-2205-118-PC_2227

Title

Plasma Focused Ion Beam and Gallium Focused Ion Beam Microscopes

A contract/lot is awarded: Yes

V.2) Award of contract

V.2.1) Date of conclusion of the contract

22 November 2022

V.2.2) Information about tenders

Number of tenders received: 2

The contract has been awarded to a group of economic operators: No

V.2.3) Name and address of the contractor

FEI UK Ltd

c/o Oakwood Corporate Services Ltd, 1 Ashley Road

Altrincham

WA14 2DT

Country

United Kingdom

NUTS code

- UK - United Kingdom

The contractor is an SME

No

V.2.4) Information on value of contract/lot (excluding VAT)

Total value of the contract/lot: £1,790,000

Section VI. Complementary information

VI.4) Procedures for review

VI.4.1) Review body

The University of Bristol

Bristol

Country

United Kingdom